

Search Notes

Application/Control No.

09/274,157

Examiner

Richard Lee

Applicant(s)/Patent under
Reexamination

MCVEIGH ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	2/7/2007	RL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR